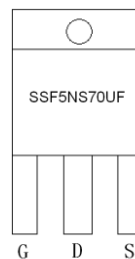
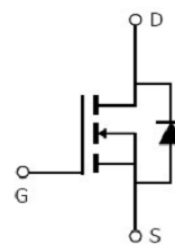


Main Product Characteristics:

V_{DSS}	700V
$R_{DS(on)}$	1.0Ω (typ.)
I_D	5A ①


TO-220F

Marking and pin Assignment

Schematic diagram
Features and Benefits:

- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance


Description:

The SSF5NS70UF series MOSFETs is a new technology, which combines an innovative technology and advance process. This new technology achieves low R_{ds(on)}, energy saving, high reliability and uniformity, superior power density and space saving.

Absolute max Rating:

Symbol	Parameter	Max.	Units
I_D @ TC = 25°C	Continuous Drain Current, V_{GS} @ 10V	5 ①	A
I_D @ TC = 100°C	Continuous Drain Current, V_{GS} @ 10V	3.1 ①	
I_{DM}	Pulsed Drain Current ②	15	
P_D @TC = 25°C	Power Dissipation ③	29	W
	Linear Derating Factor	0.23	W/°C
V_{DS}	Drain-Source Voltage	700	V
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy @ L=144.4mH	173	mJ
I_{AS}	Avalanche Current @ L=144.4mH	1.55	A
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C

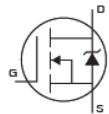
Thermal Resistance

Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	—	4.3	$^{\circ}C/W$
$R_{\theta JA}$	Junction-to-ambient ($t \leq 10s$) ④	—	62	$^{\circ}C/W$

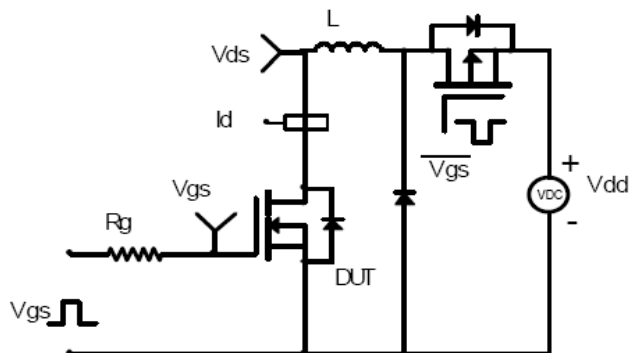
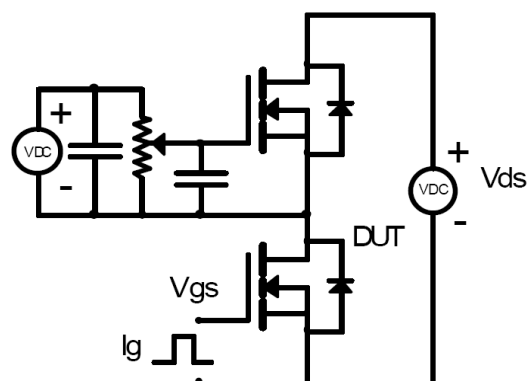
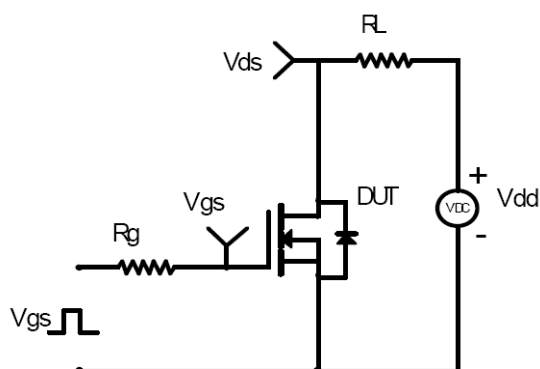
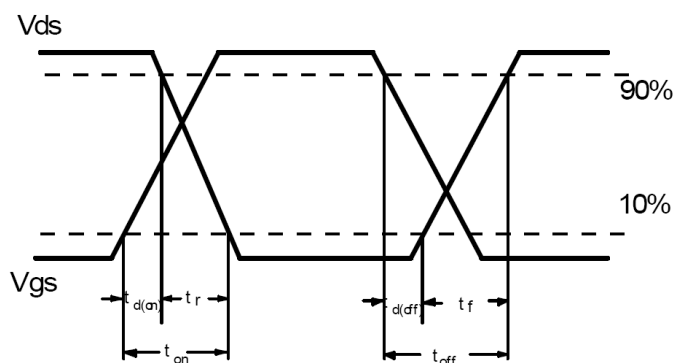
Electrical Characterizes @ $T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	700	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	1.0	1.25	Ω	$V_{GS}=10V, I_D = 1A$ $T_J = 125^{\circ}C$
		—	2.3	—		
		—	1.14	1.4	Ω	$V_{GS}=10V, I_D = 2.8A$ $T_J = 125^{\circ}C$
		—	3.0	—		
$V_{GS(th)}$	Gate threshold voltage	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu A$ $T_J = 125^{\circ}C$
		—	2.3	—		
I_{DSS}	Drain-to-Source leakage current	—	—	1	μA	$V_{DS} = 700V, V_{GS} = 0V$ $T_J = 125^{\circ}C$
		—	—	50		
I_{GSS}	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 30V$ $V_{GS} = -30V$
		—	—	-100		
Q_g	Total gate charge	—	9.8	—	nC	$I_D = 5A,$ $V_{DS}=200V,$ $V_{GS} = 10V$
Q_{gs}	Gate-to-Source charge	—	2.7	—		
Q_{gd}	Gate-to-Drain("Miller") charge	—	3.6	—		
$t_{d(on)}$	Turn-on delay time	—	9.2	—	ns	$V_{GS}=10V, V_{DS} = 400V,$ $R_{GEN}=10.2\Omega, I_D = 1.5A$
t_r	Rise time	—	5.6	—		
$t_{d(off)}$	Turn-Off delay time	—	23	—		
t_f	Fall time	—	13	—		
C_{iss}	Input capacitance	—	343	—	pF	$V_{GS} = 0V$ $V_{DS} = 100V$ $f = 1MHz$
C_{oss}	Output capacitance	—	18	—		
C_{rss}	Reverse transfer capacitance	—	2.9	—		

Source-Drain Ratings and Characteristics

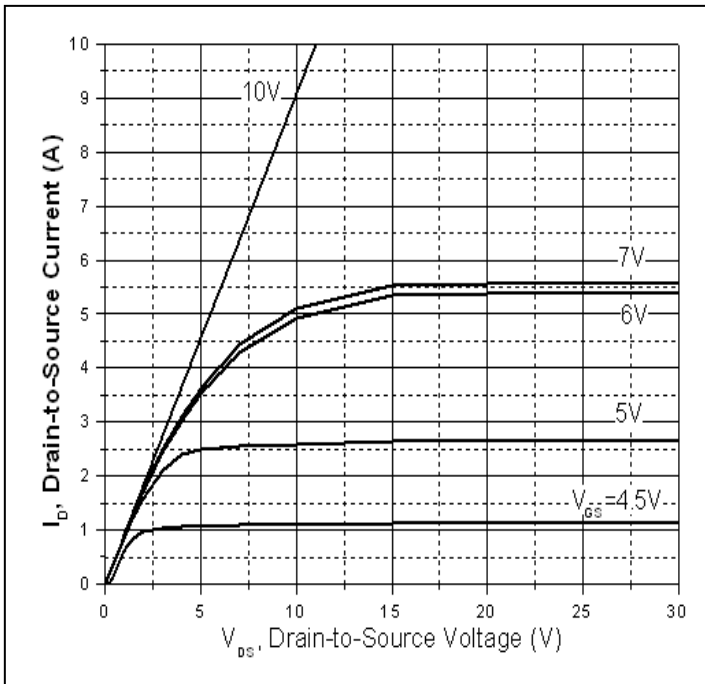
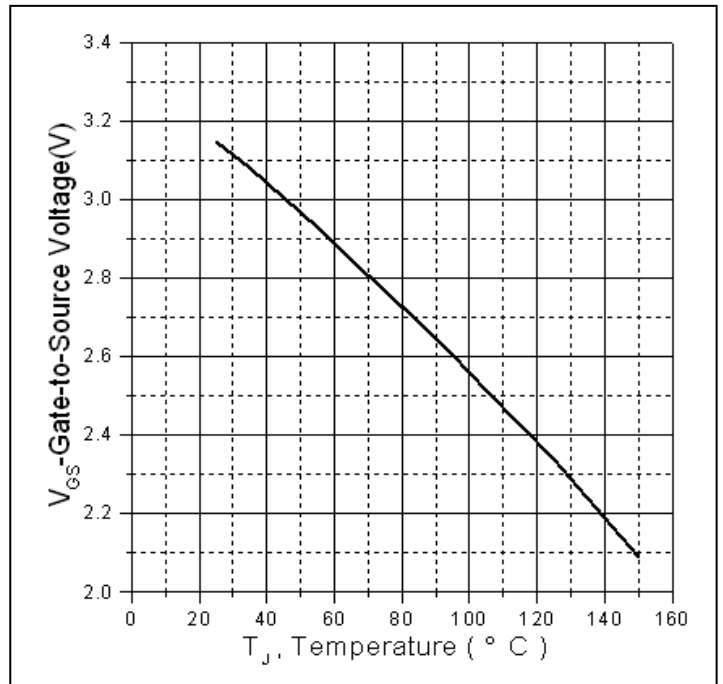
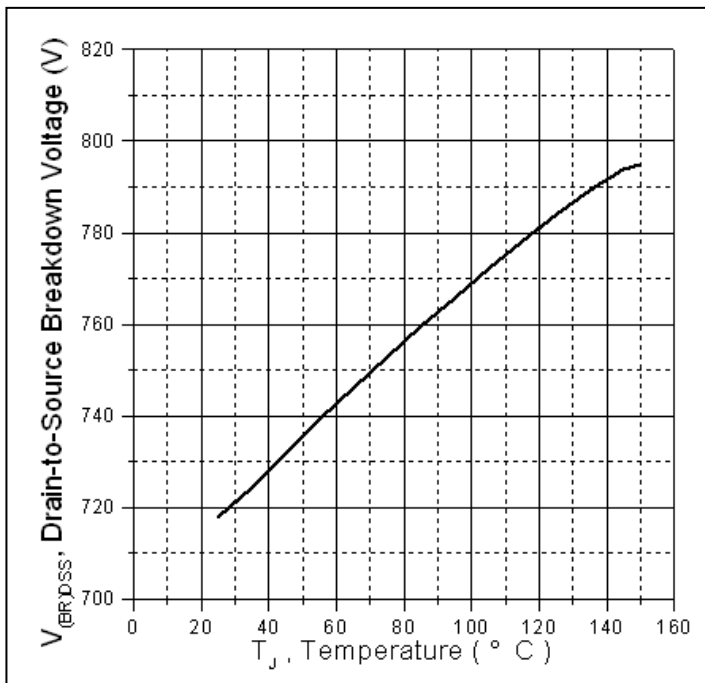
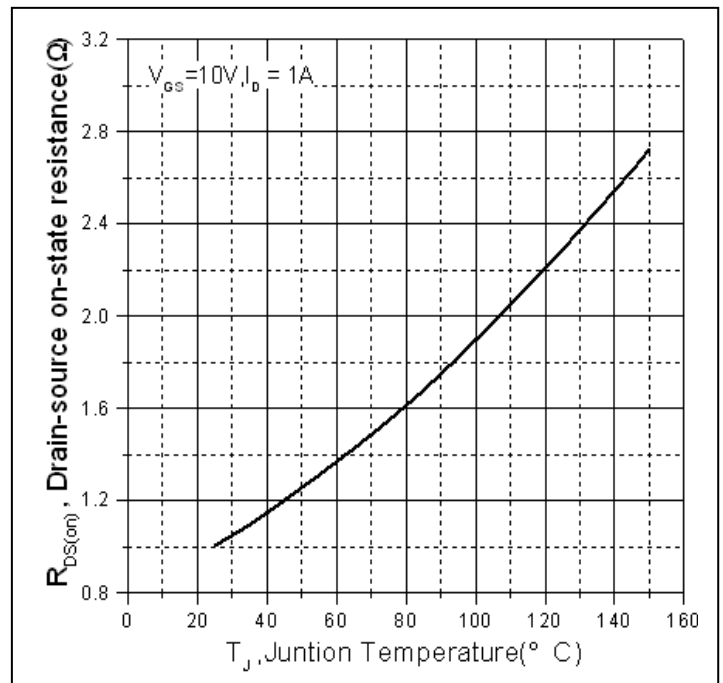
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	5 ①	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{SM}	Pulsed Source Current (Body Diode)	—	—	15	A	
V_{SD}	Diode Forward Voltage	—	0.83	1.2	V	$I_S=2.8A, V_{GS}=0V$
t_{rr}	Reverse Recovery Time	—	99	—	nS	$T_J = 25^{\circ}C, I_F = 1.5A,$
Q_{rr}	Reverse Recovery Charge	—	466	—	nC	$di/dt = 100A/\mu s$

Test circuits and Waveforms

EAS Test Circuit:

Gate charge test circuit:

Switching Time Test Circuit:

Switching Waveforms:


Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$

Typical electrical and thermal characteristics

Figure 1: Typical Output Characteristics

Figure 2. Gate to source cut-off voltage

Figure 3. Drain-to-Source Breakdown Voltage Vs. Case Temperature

Figure 4: Normalized On-Resistance Vs. Case Temperature

Typical electrical and thermal characteristics

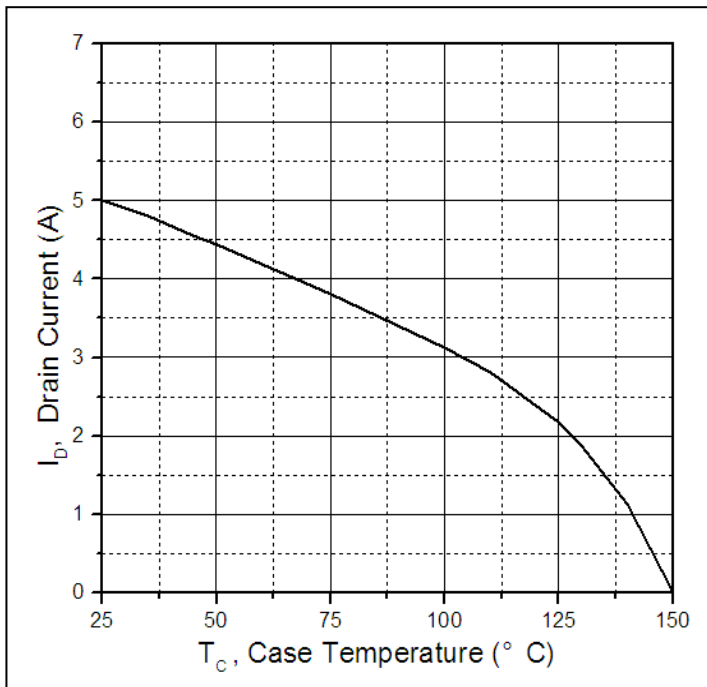


Figure 5. Maximum Drain Current Vs. Case Temperature

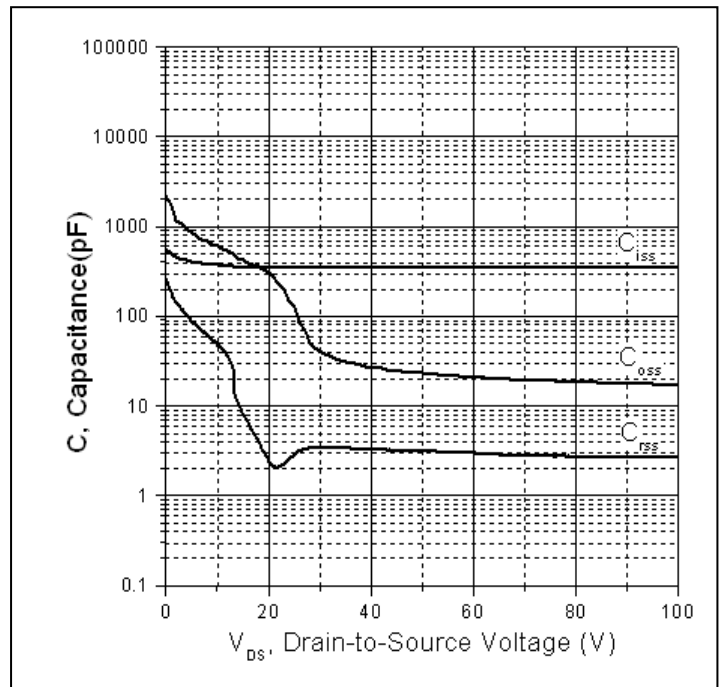


Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage

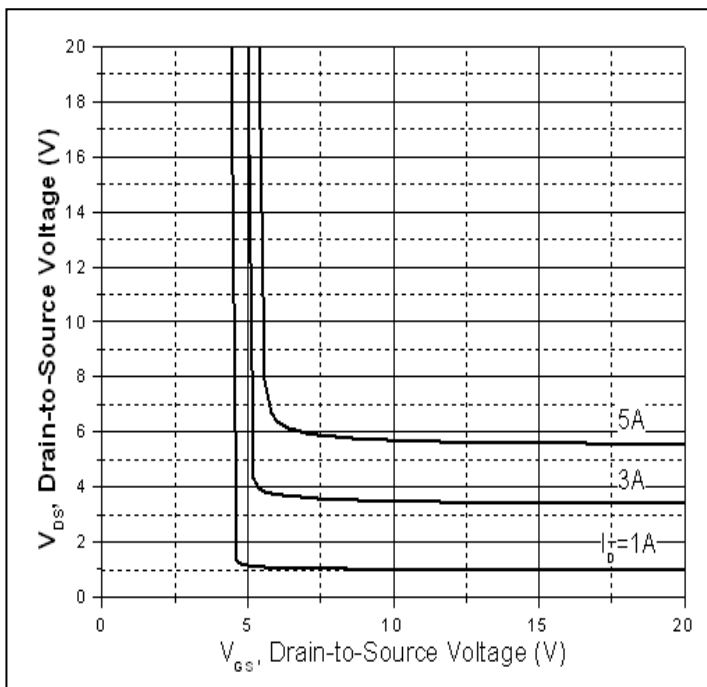


Figure 7. Drain-to-Source Voltage Vs. Gate-to-Source Voltage

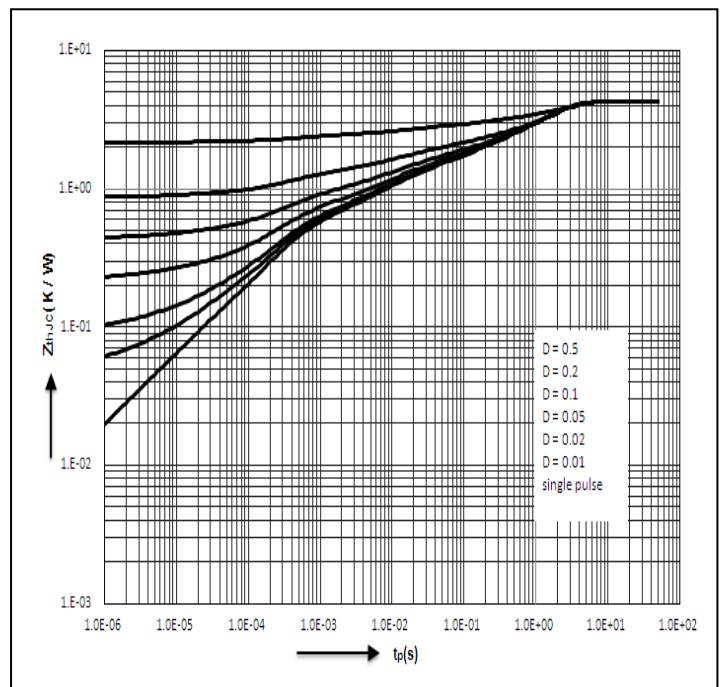
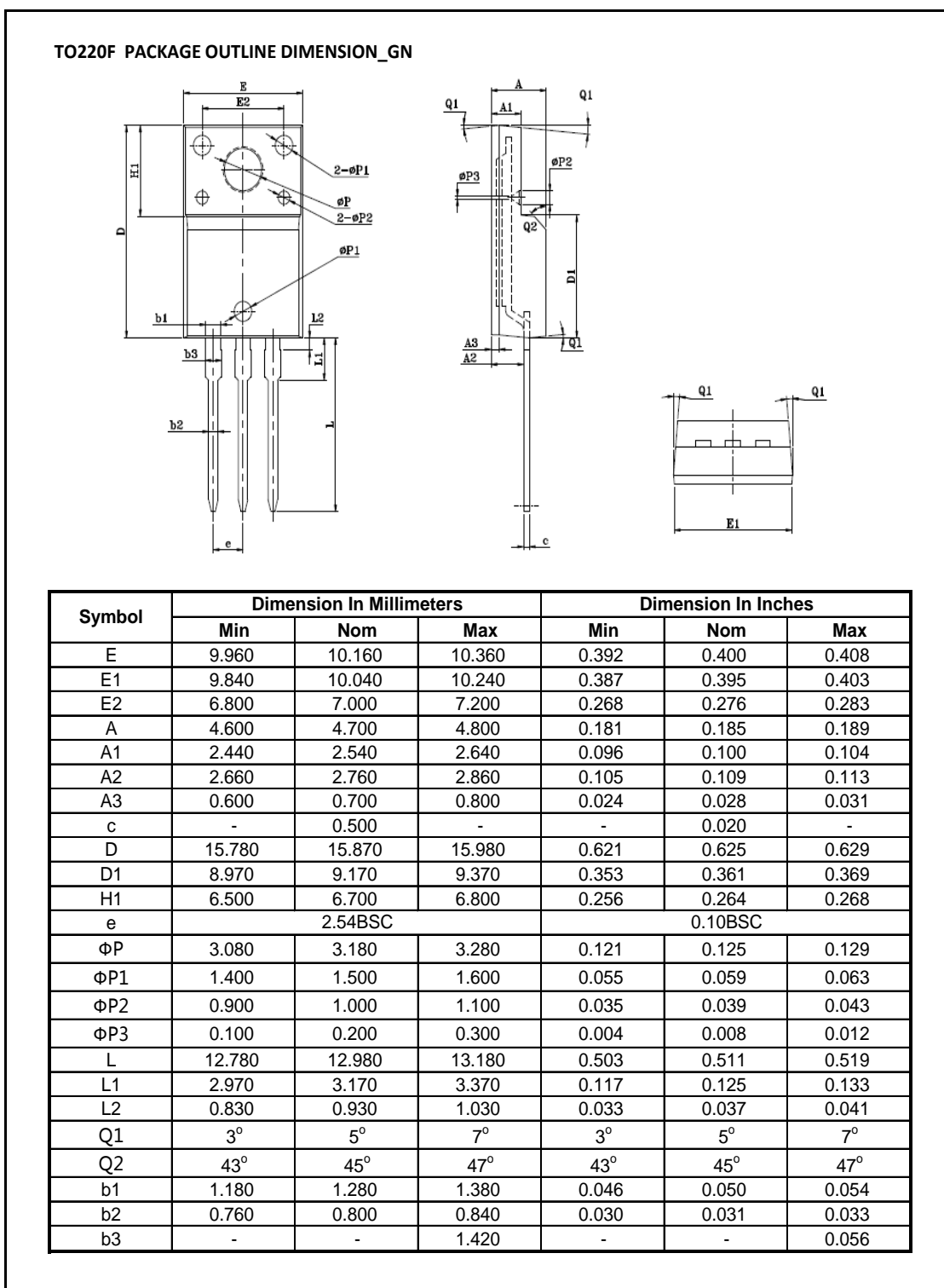


Figure 8. Maximum Effective Transient Thermal Impedance, Junction-to-Case

Mechanical Data:


Ordering and Marking Information
Device Marking: SSF5NS70UF
Package (Available)
TO-220F
Operating Temperature Range
C : -55 to 150 °C
Devices per Unit

Package Type	Units/Tube	Tubes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO-220F	50	20	1000	6	6000

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High Temperature Reverse Bias(HTRB)	T _j =125°C to 150°C @ 80% of Max V _{DSS} /V _{CES} /VR	168 hours 500 hours 1000 hours	3 lots x 77 devices
High Temperature Gate Bias(HTGB)	T _j =150°C @ 100% of Max V _{GSS}	168 hours 500 hours 1000 hours	3 lots x 77 devices

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Technical Support:

Technical@silikron.com

Suzhou Silikron Semiconductor Corp.

11A, 428 Xinglong Street, Suzhou Industrial Park, P.R.China

TEL: (86-512) 62560688

FAX: (86-512) 65160705

E-mail: Sales@silikron.com